

Daniel Lizzit

List of Publications by Year in descending order

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Version: 2024-02-01

42
papers

643
citations

623699

14
h-index

642715

23
g-index

42
all docs

42
docs citations

42
times ranked

918
citing authors

#	ARTICLE	IF	CITATIONS
1	Transition metal carbides (MXenes) for efficient NiO-based inverted perovskite solar cells. Nano Energy, 2021, 82, 105771.	16.0	74
2	Epitaxial growth of single-orientation high-quality MoS ₂ monolayers. 2D Materials, 2018, 5, 035012.	4.4	65
3	Novel single-layer vanadium sulphide phases. 2D Materials, 2018, 5, 045009.	4.4	48
4	Performance Benchmarking and Effective Channel Length for Nanoscale InAs, $\text{In}_{0.53}\text{Ga}_{0.47}\text{As}$, and sSi n-MOSFETs. IEEE Transactions on Electron Devices, 2014, 61, 2027-2034.	3.0	39
5	Ion Implantation as an Approach for Structural Modifications and Functionalization of Ti ₃ C ₂ T _x MXenes. ACS Nano, 2021, 15, 4245-4255.	14.6	37
6	Performance projection of III-V ultra-thin-body, FinFET, and nanowire MOSFETs for two next-generation technology nodes. , 2016, , .		29
7	Spin Structure of K Valleys in Single-Layer WS_2	7.8	28
8	80% Valley Polarization of Free Carriers in Singly Oriented Single-Layer WS_2 on Au(111). Physical Review Letters, 2019, 123, 236802.	7.8	27
9	A new formulation for surface roughness limited mobility in bulk and ultra-thin-body metal-oxide-semiconductor transistors. Journal of Applied Physics, 2014, 116, .	2.5	26
10	An Improved Surface Roughness Scattering Model for Bulk, Thin-Body, and Quantum-Well MOSFETs. IEEE Transactions on Electron Devices, 2016, 63, 2306-2312.	3.0	20
11	Analysis of the Performance of n-Type FinFETs With Strained SiGe Channel. IEEE Transactions on Electron Devices, 2013, 60, 1884-1891.	3.0	19
12	Photoemission investigation of oxygen intercalated epitaxial graphene on Ru(0001). Surface Science, 2018, 678, 57-64.	1.9	18
13	Growth and structure of singly oriented single-layer tungsten disulfide on Au(111). Physical Review Materials, 2019, 3, .	2.4	18
14	The impact of interface states on the mobility and drive current of WS_2	1.4	17
15	Compositional Phase Change of Early Transition Metal Diselenide (VSe_2 and $TjETQq_1$)	3.7	17
16	Surface roughness limited mobility modeling in ultra-thin SOI and quantum well III-V MOSFETs. , 2013, , .		14
17	Mixed Cation Halide Perovskite under Environmental and Physical Stress. Materials, 2021, 14, 3954.	2.9	14
18	Momentum-resolved linear dichroism in bilayer MoS_2	3.2	13

#	ARTICLE	IF	CITATIONS
19	Layer and orbital interference effects in photoemission from transition metal dichalcogenides. <i>Physical Review B</i> , 2019, 100, .	3.2	11
20	Benchmarking of 3-D MOSFET Architectures: Focus on the Impact of Surface Roughness and Self-Heating. <i>IEEE Transactions on Electron Devices</i> , 2018, 65, 3646-3653.	3.0	10
21	Simulation analysis of III–V n-MOSFETs: Channel materials, Fermi level pinning and biaxial strain. , 2014, , .		9
22	Improved surface-roughness scattering and mobility models for multi-gate FETs with arbitrary cross-section and biasing scheme. <i>Journal of Applied Physics</i> , 2017, 121, .	2.5	9
23	Spectroscopic view of ultrafast charge carrier dynamics in single- and bilayer transition metal dichalcogenide semiconductors. <i>Journal of Electron Spectroscopy and Related Phenomena</i> , 2021, 250, 147093.	1.7	9
24	Dual-Route Hydrogenation of the Graphene/Ni Interface. <i>ACS Nano</i> , 2019, 13, 1828-1838.	14.6	8
25	Electronâ€“phonon coupling in single-layer MoS2. <i>Surface Science</i> , 2019, 681, 64-69.	1.9	7
26	Interfacial two-dimensional oxide enhances photocatalytic activity of graphene/titania via electronic structure modification. <i>Carbon</i> , 2020, 157, 350-357.	10.3	7
27	Resistance hysteresis correlated with synchrotron radiation surface studies in atomic sp² layers of carbon synthesized on ferroelectric (001) lead zirconate titanate in an ultrahigh vacuum. <i>RSC Advances</i> , 2020, 10, 1522-1534.	3.6	7
28	Limitations to Electrical Probing of Spontaneous Polarization in Ferroelectric-Dielectric Heterostructures. <i>IEEE Journal of the Electron Devices Society</i> , 2022, 10, 324-333.	2.1	7
29	Strong ferromagnetic coupling and tunable easy magnetization directions of FexCo1âˆ“x layer(s) intercalated under graphene. <i>Applied Surface Science</i> , 2020, 527, 146599.	6.1	5
30	Anisotropic strain in epitaxial single-layer molybdenum disulfide on Ag(110). <i>Nanoscale</i> , 2021, 13, 18789-18798.	5.6	5
31	Surface roughness limited mobility in multi-gate FETs with arbitrary cross-section. , 2016, , .		4
32	Quasi-Ballistic Γ - and L-Valleys Transport in Ultrathin Body Strained (111) GaAs nMOSFETs. <i>IEEE Transactions on Electron Devices</i> , 2016, 63, 4685-4692.	3.0	4
33	Growth Mechanism and Thermal Stability of a MoS₂â€“Graphene Interface: A High-Resolution Core-Level Photoelectron Spectroscopy Study. <i>Journal of Physical Chemistry C</i> , 2020, 124, 20889-20897.	3.1	4
34	CO adsorption, reduction and oxidation on Pb(Zr,Ti)O3(001) surfaces associated with negatively charged gold nanoparticles. <i>Catalysis Today</i> , 2021, 366, 141-154.	4.4	4
35	Toward computationally efficient Multi-Subband Monte Carlo simulations of nanoscale MOSFETs. , 2013, , .		3
36	The impact of interface states on the mobility and the drive current of III-V MOSFETs. , 2014, , .		2

#	ARTICLE	IF	CITATIONS
37	Improved surface roughness modeling and mobility projections in thin film MOSFETs. , 2015, , .		2
38	State-of-the-art semi-classical Monte Carlo method for carrier transport in nanoscale transistors. , 2015, , .		2
39	A Multi-Subband Monte Carlo study of electron transport in strained SiGe n-type FinFETs. , 2012, , .		1
40	On the optimization of SiGe and III-V compound hetero-junction Tunnel FET devices. , 2013, , .		1
41	New device concepts, transistor architectures and materials for high performance and energy efficient CMOS circuits in the forthcoming era of 3D integrated circuits. , 2018, , .		0
42	Modeling Nanoscale III-V Channel MOSFETs with the Self-Consistent Multi-Valley/Multi-Subband Monte Carlo Approach. Electronics (Switzerland), 2021, 10, 2472.	3.1	0